

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Rajesh S. Nair et al
FILED: Concurrently Herewith
FOR: HIGH VOLTAGE LATERAL FET STRUCTURE WITH
IMPROVED ON RESISTANCE PERFORMANCE
Date: 3/8/2004

DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.56

Honorable Assistant Commissioner for Patents
Washington, D.C. 20231

SIR:

It is respectfully requested that the prior art listed on FORM PTO-1449 be considered in the examination of the subject application and made of record therein. A copy of the listed prior art is not enclosed.

No representation is made or intended that the listed prior art enclosed herewith is material to patentability of the subject patent application.

No representation is made or intended that a search has been made or that no better prior art than that listed is available.

Respectfully submitted,
Rajesh S. Nair et al



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Form PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use Several Sheets if Necessary)	ATTY. DOCKET NO.	SERIAL NO.
	ONS00507	
	APPLICANT Rajesh S. Nair et al.	
	FILING DATE	GROUP
	Concurrently Herewith	

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing date (If appropriate)
AA	5 2 9 4 8 2 4	3/15/1994	Okada	H01L	29/82	
AB	6 0 9 7 0 6 3	8/1/2000	Fujihira	H01L	29/94	
AC	6 4 4 8 6 2 5	9/10/2002	Hossain et al.	H01L	23/58	
AD	6 5 0 9 2 2 0	1/21/2003	Disney	H01L	21/336	
AE	6 5 6 6 7 0 9	5/20/2003	Fujihira	H01L	29/76	
AF	6 5 8 9 8 4 5	7/8/2003	Nair et al.	H01L	21/336	
AG	6 6 3 9 2 7 7	10/28/2003	Rumennik et al.	H01L	29/76	
AH				H01L		
AI						
AJ						
AK						
AL						
AM						

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document #	Date	Country	Class/subclass	Translation Yes - No
AN					
AO					
AP					
AQ					
AR					

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AS	
AT	
AU	
AV	
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance *and* not considered. Include copy of this form with next communication to applicant.